



National Institute of Technology, Tiruchirappalli

Tiruchirappalli 620015

Sophisticated Instrumentation Facility

Atomic Force Microscope (AFM) - Testing Charge Details

Category	Internal (Inside NITT)	External (Other Academic Institutes)	Government and R&D Lab	Industry
Basic Mode	Rs. 750/sample	Rs. 1125/sample	Rs. 1500/sample	Rs. 2250/sample
Advanced Mode	Rs. 1000/ Sample	Rs. 1500/sample	Rs. 2000/sample	Rs. 3000/sample

Important Notes:

- All the mentioned charges are inclusive of GST.
- All testing charge calculations will be carried out exclusively by SIF staff.
- Please contact SIF via email or phone to confirm the final charges.
- Payments made without prior confirmation from the SIF office will not be refunded.